Notice of References Cited Application/Control No. O9/931,290 Examiner Djenane M Bayard Applicant(s)/Patent Under Reexamination KISTLER, MICHAEL DAVID Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0116583	08-2002	Copeland et al.	711/133
	В	US-2002/0049918	04-2002	Kaxiras et al.	713/300
	C	US-5,692,197	11-1997	Narad et al.	713/323
	D	US-2004/0174814	09-2004	Futral, William T.	370/231
	E	US-5,613,071	03-1997	Rankin et al.	707/10
	F	US-2002/0184403	12-2002	Dahlin et al.	709/316
	G	US-4,578,774	03-1986	Muller, Arno	713/324
-	Н	US-2002/0107935	08-2002	Lowery et al.	709/216
	1	US-2002/0091826	07-2002	Comeau et al.	709/226
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Φ.					
	σ					
	R					
	Ø					·
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	כ						
	٧						
	8						
	Х						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.